

**Search Notes**

Application/Control No.

10/525,190

Examiner

Tuyen Q. Tra

Applicant(s)/Patent under  
Reexamination

FUJIMATSU ET AL.

Art Unit

2873

**SEARCHED**

Class	Subclass	Date	Examiner
351	203 205 206 209 210 221	2/23/2007	TT
382	117 154 209	2/27/2007	TT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Same as	above	2/27/2007	TT
USPAT and USPG-PUB		2/23/2007	TT

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
TEXT SEARCH ON EAST (USPAT, USPG-PUB, EPO, DERWENT, JPO)	2/23/2007	TT
INVENTOR SEARCH	2/23/2007	TT
INTERFERENCE SEARCH HISTORY PRINTOUT	2/23/2007	TT